

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/508,793 OHBA ET AL.	
		Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,389,101 B1	05-2002	Levine et al.	378/85
*	B US-6,278,764 B1	08-2001	Barbee et al.	378/84
*	C US-5,604,782	02-1997	Cash, Jr., Webster C.	378/85
*	D US-5,450,463	09-1995	Iketaki, Yoshinori	378/43
*	E US-5,434,901	07-1995	Nagai et al.	378/43
*	F US-5,241,426	08-1993	Mochimaru et al.	359/869
*	G US-5,222,113	06-1993	Thieme et al.	378/43
*	H US-5,138,158	08-1992	Ninomiya et al.	250/305
*	T US-5,132,994	07-1992	Kato, Mikiko	378/43
*	J US-4,969,725	11-1990	Sumiya et al.	378/145
*	K US-4,940,319	07-1990	Ueda et al.	359/853
*	L US-3,821,556	06-1974		378/43
*	M US-2,759,106	08-1956	HANS WOLTER	378/43

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages	
U	F. Bridou and J. P. Marioge, J. Optics 15(4), 270-280 (1984).	
V	Michael J. Boyle and Harlow G. Ahlstrom, Rev. Sci. Instrum. 49(6), 746 (1978).	
W		
X		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.